

Updates on 1 GeV beam π^+ -Ar inclusive cross section measurement

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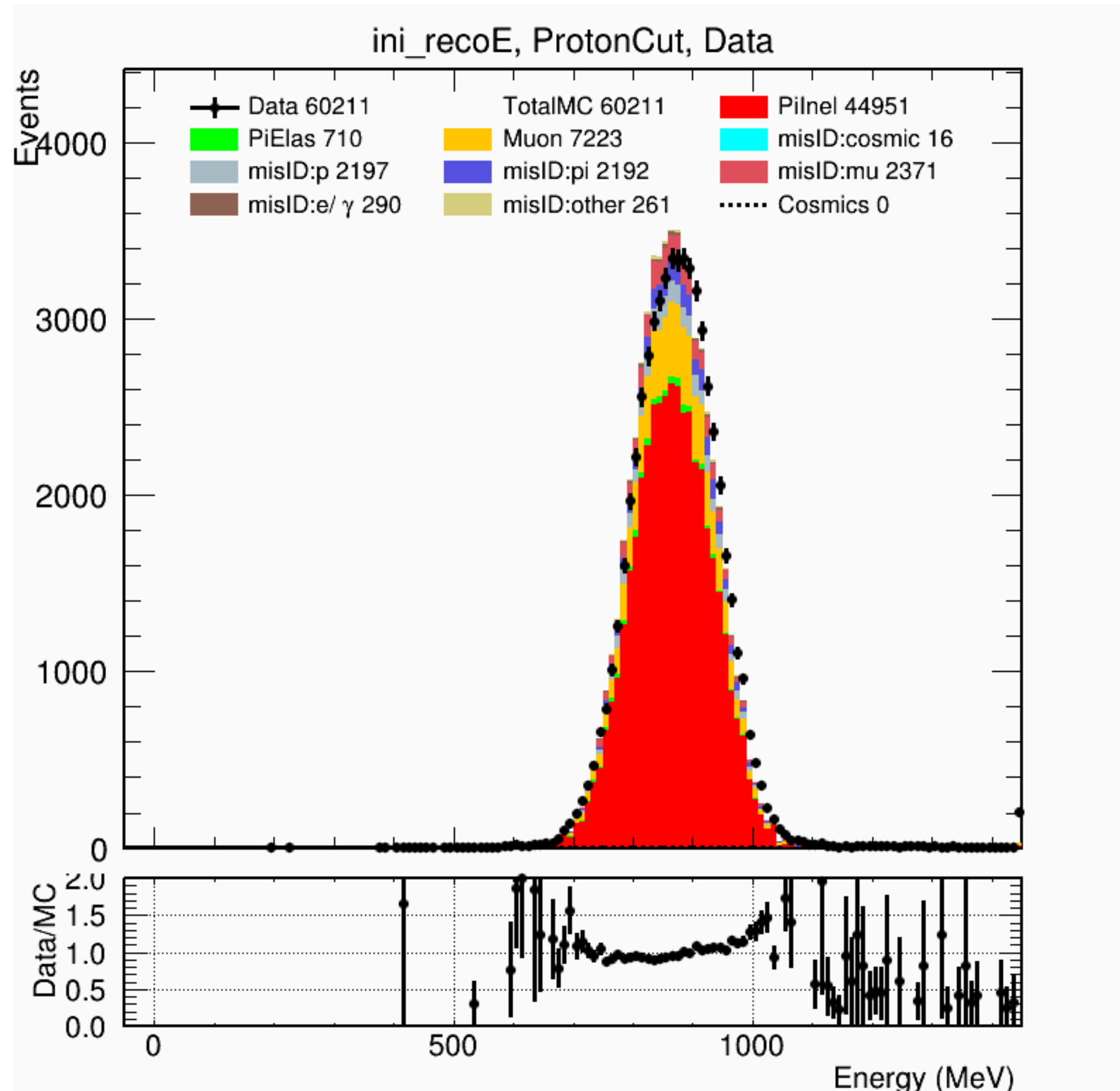


Sungbin's reweighting

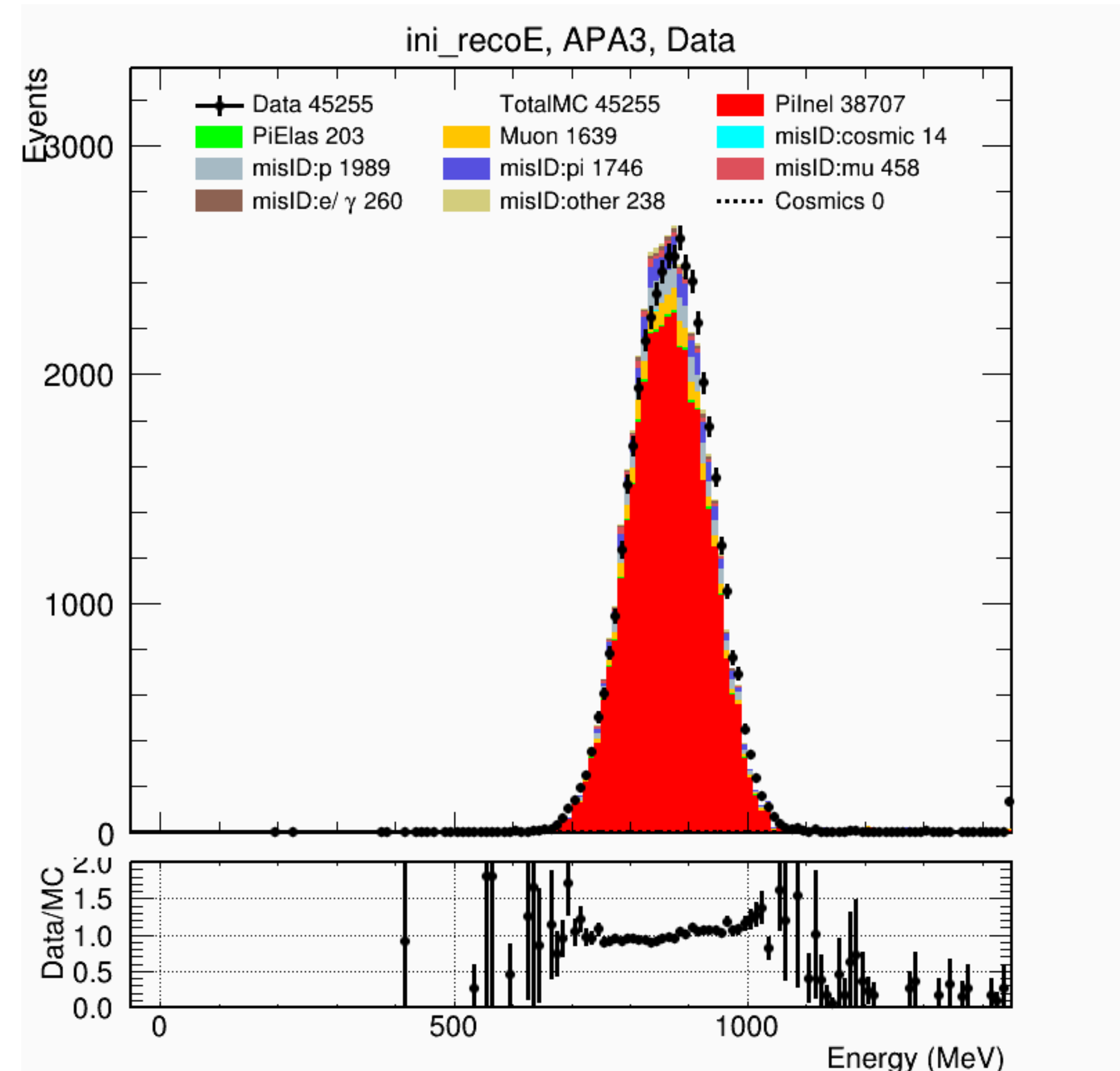
- Fit **MC true** beam momentum with a $\text{Gaus}(\mu_1, \sigma_1)$
- Fit **MC instrumented** beam momentum with a $\text{Gaus}(\mu_2, \sigma_2)$
- Derive the required resolution $\sigma_r = \sqrt{\sigma_2^2 - \sigma_1^2}$
- Fit **data instrumented** beam momentum with a $\text{Gaus}(\mu_3, \sigma_3)$
- Estimate the **data true** beam momentum $\sigma_4 = \sqrt{\sigma_3^2 - \sigma_r^2}$
- Reweight **MC true** to **data true** by assigning the factor $\text{Gaus}(\mu_1, \sigma_4) / \text{Gaus}(\mu_1, \sigma_1)$

- Sungbin assumes the resolution for data and MC is the same, because “it is only related with scintillation fibre width of beam spectrometer”.
- Plan to consider difference in μ as well.

Using Sungbin's parameters $\text{weight}=\text{Gaus}(1007, 68.17)/\text{Gaus}(1007, 57.7)$



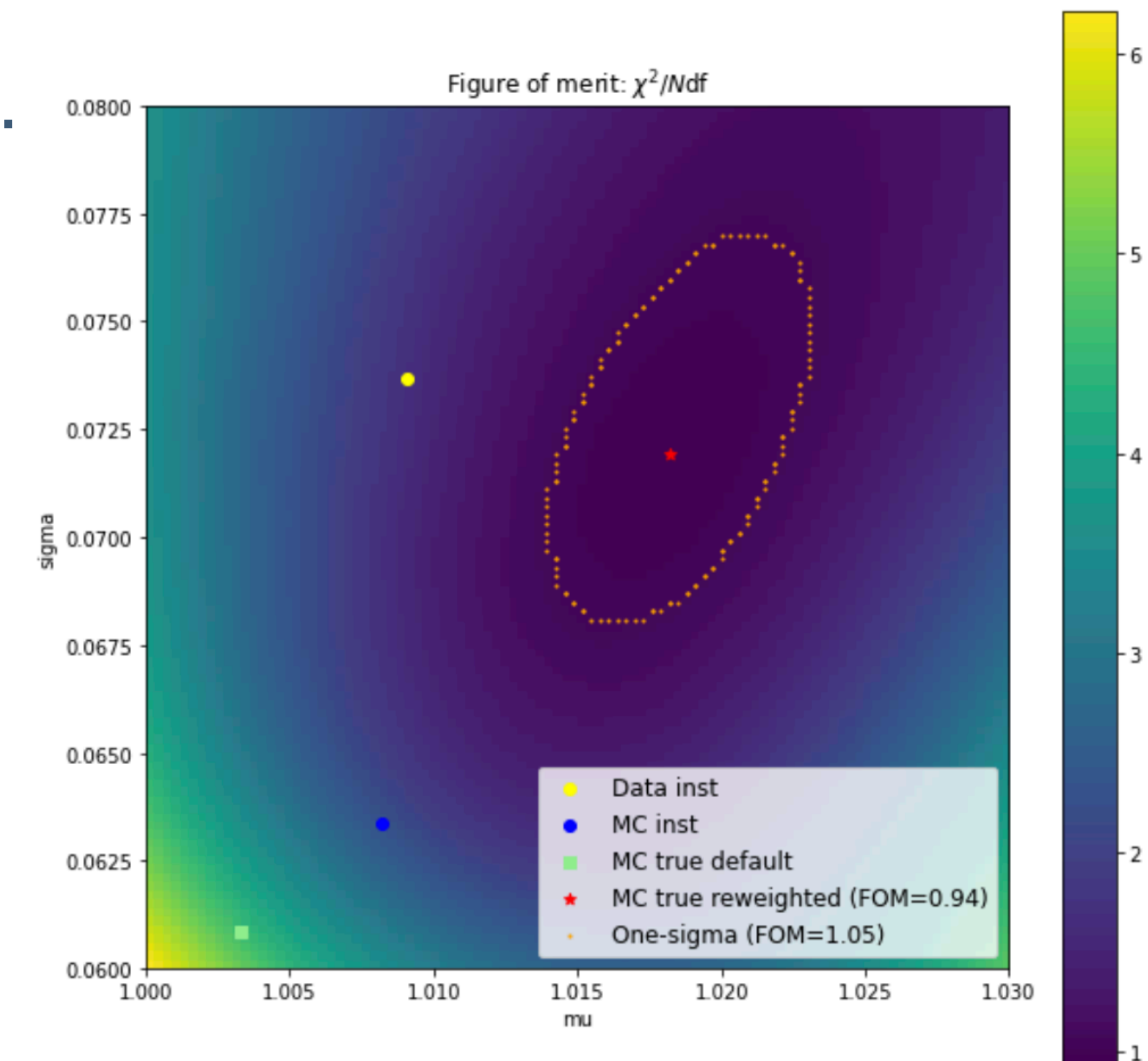
Before muon cuts



After muon cuts

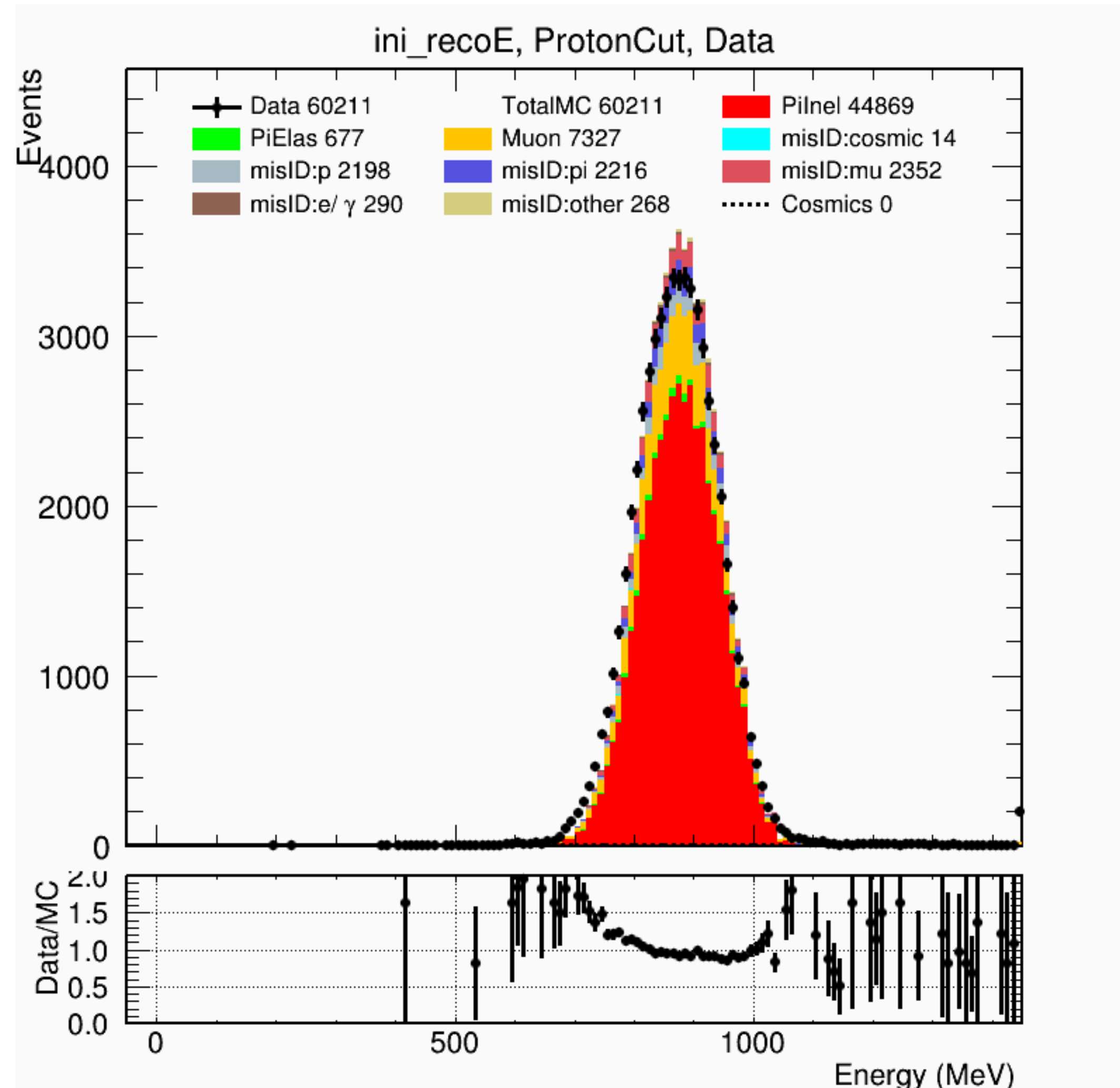
My reweighting procedure

- Select stopping muon sample in both data and MC as standard candle
- Calculate their front-face KE using reco_trklen
- Reweight MC true beam momentum for the lowest chi2 on KEff_from_trklen for data/MC
- Now we expect data and MC have the same true beam momentum.
- We assume this result from muons can also be applied to pions.

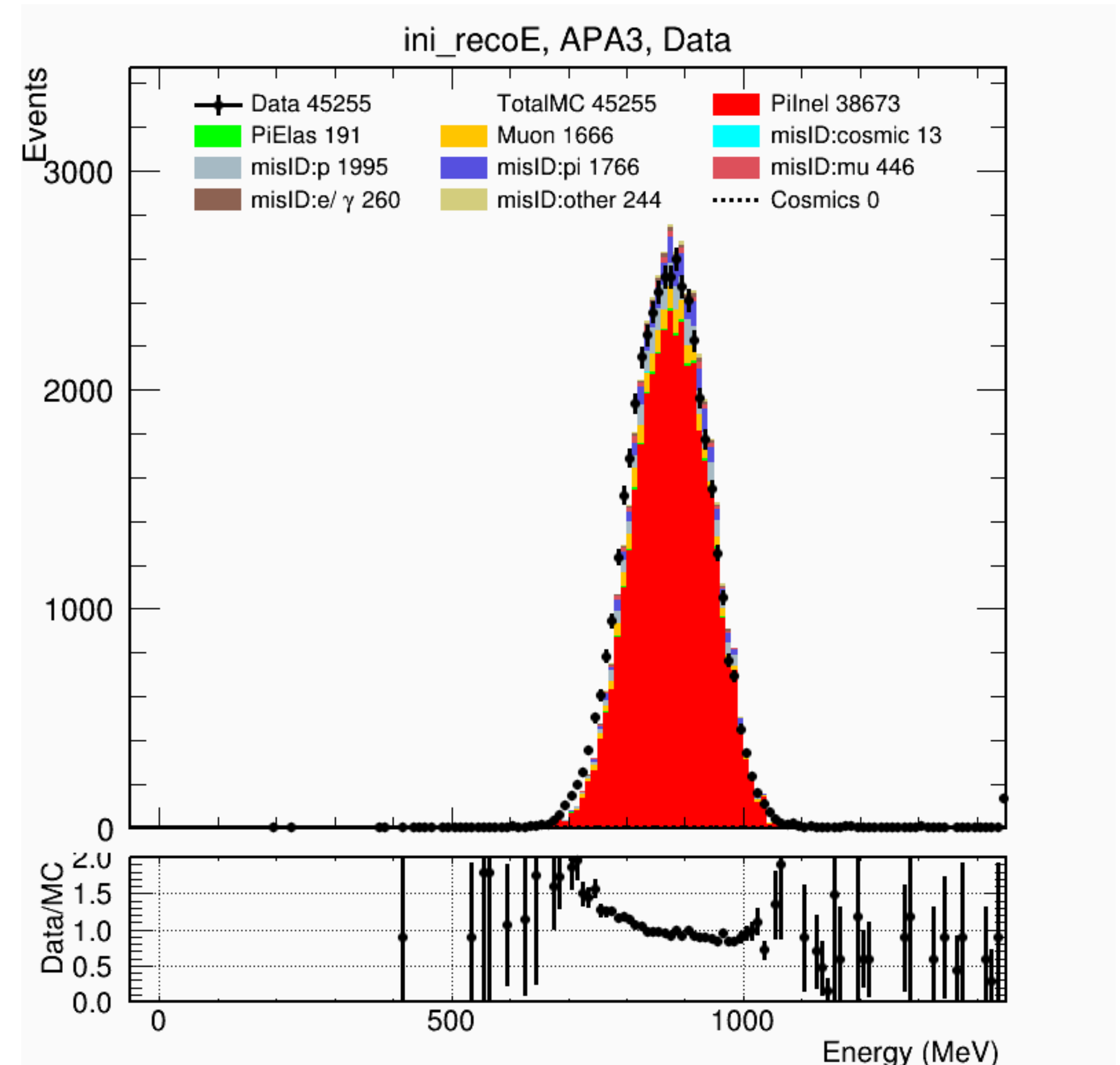


Results

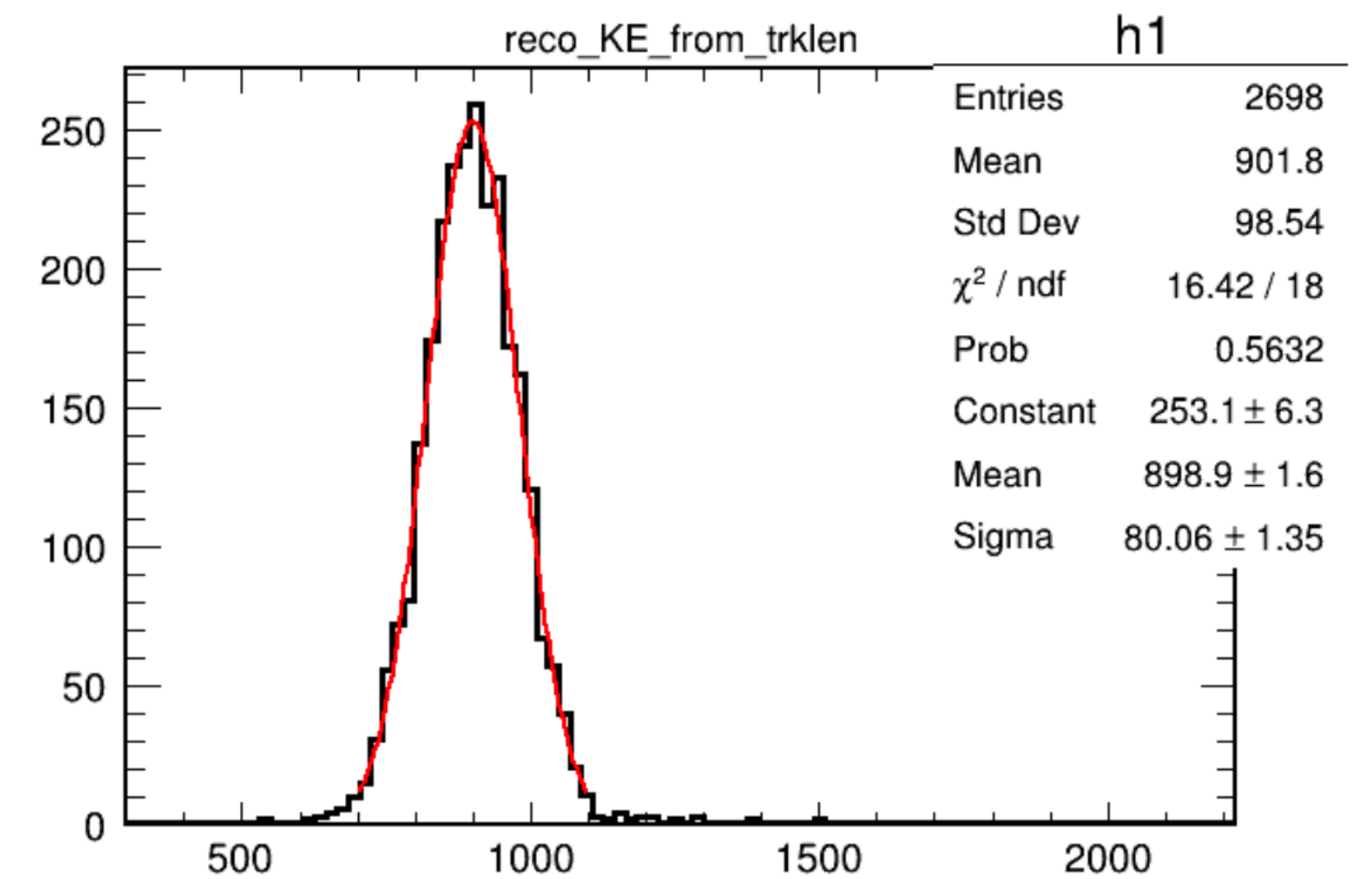
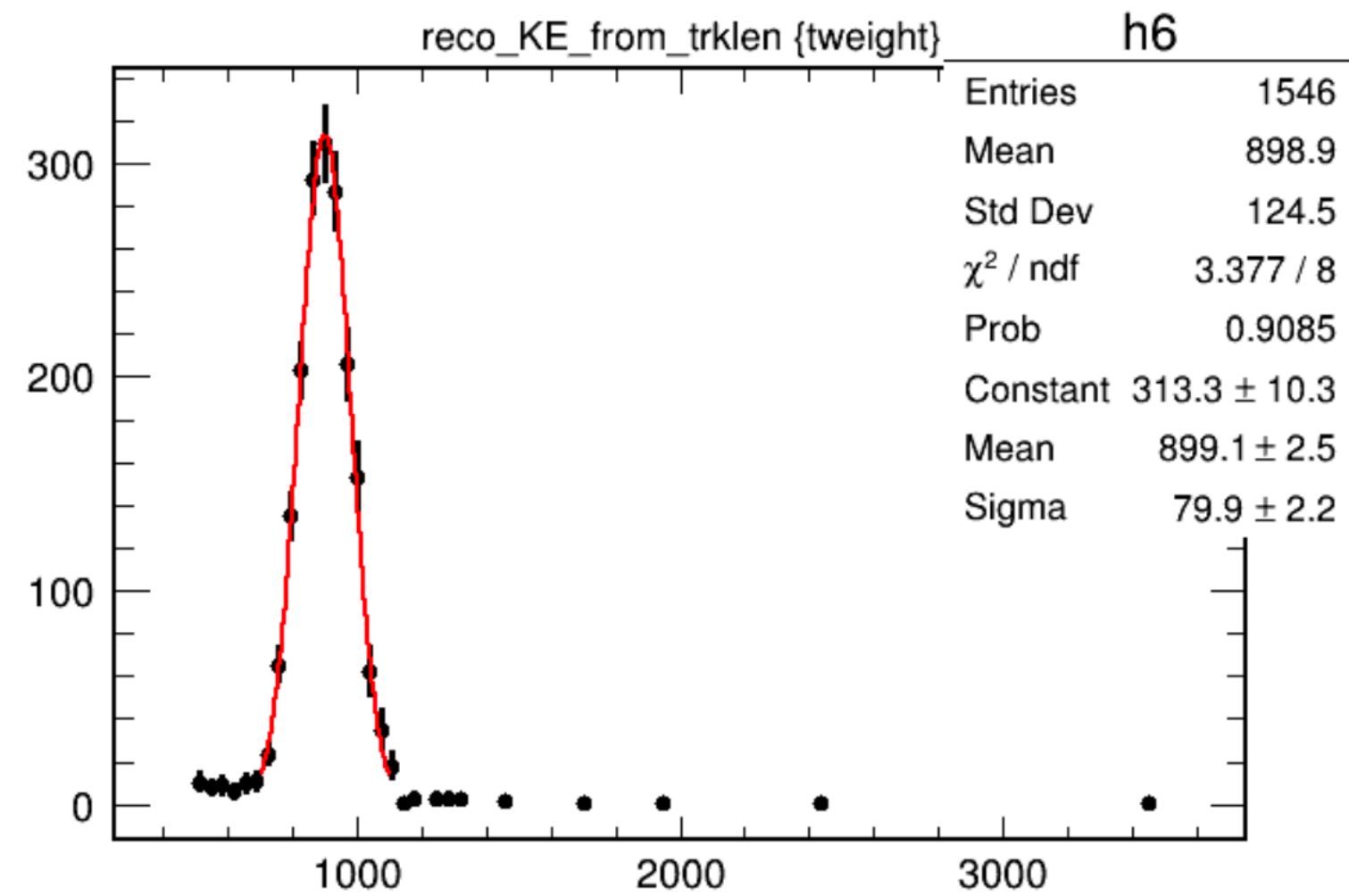
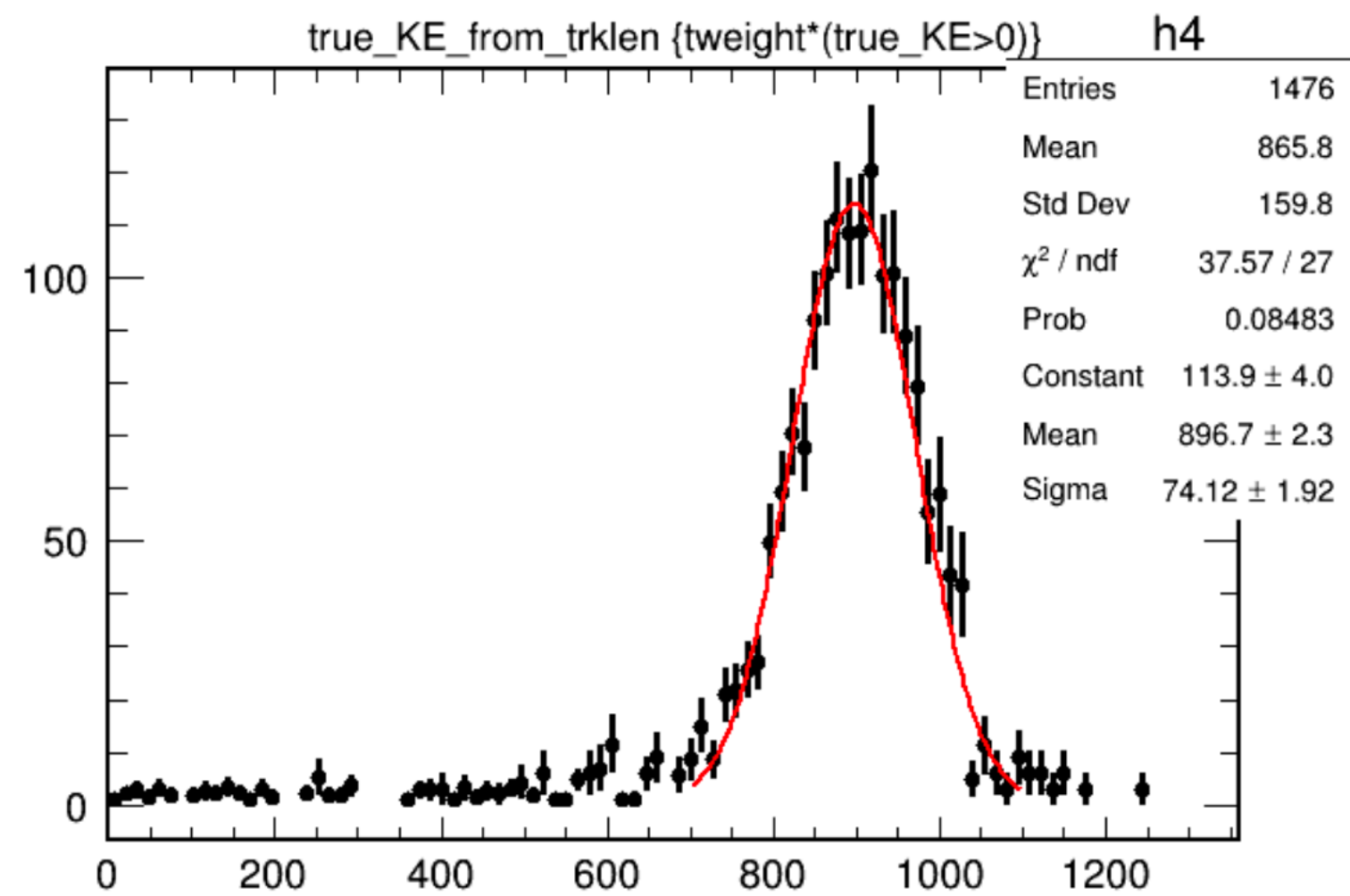
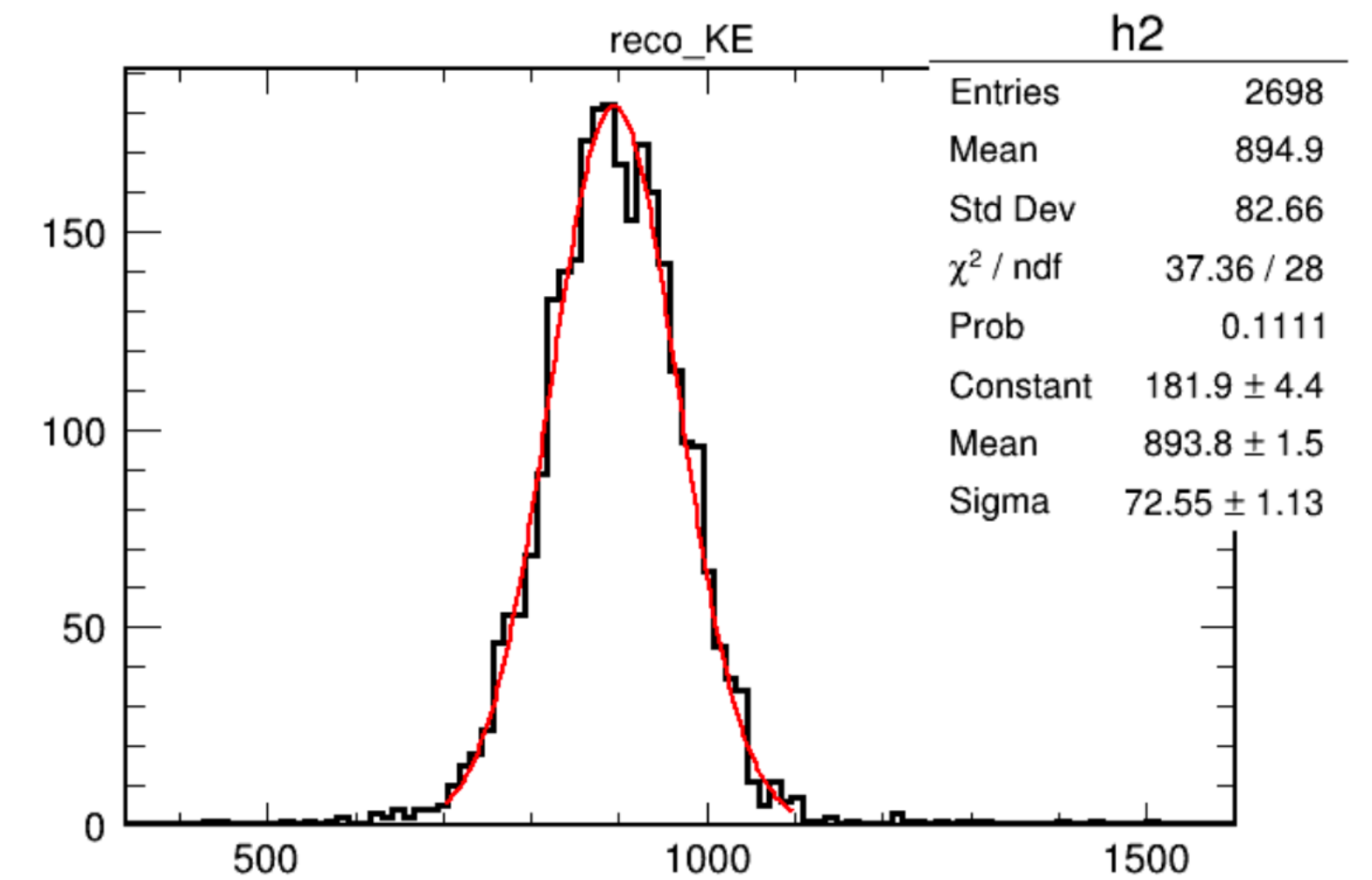
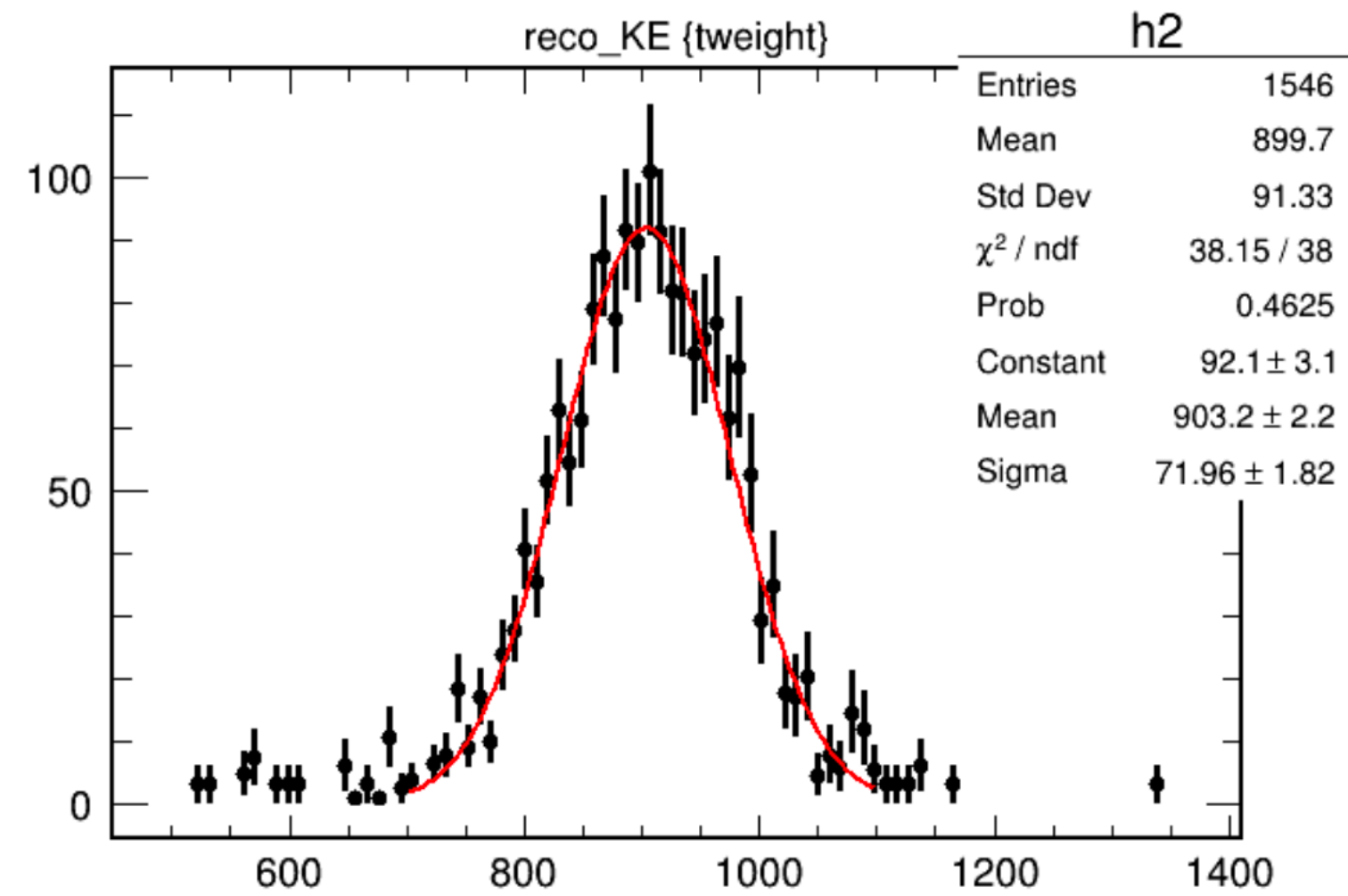
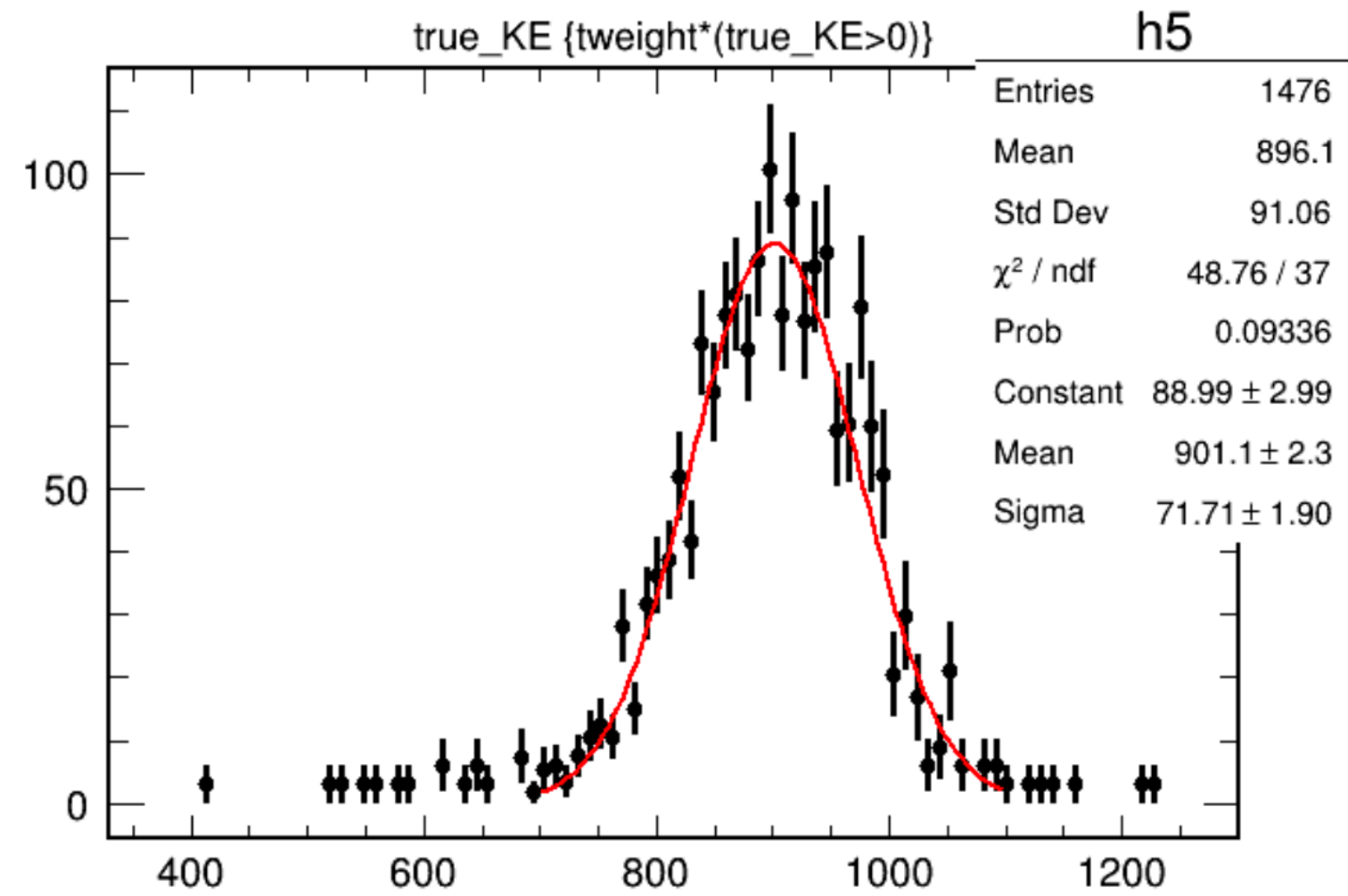
$$\text{weight} = \text{Gaus}(1018.18, 71.92) / \text{Gaus}(1003.3, 60.9)$$

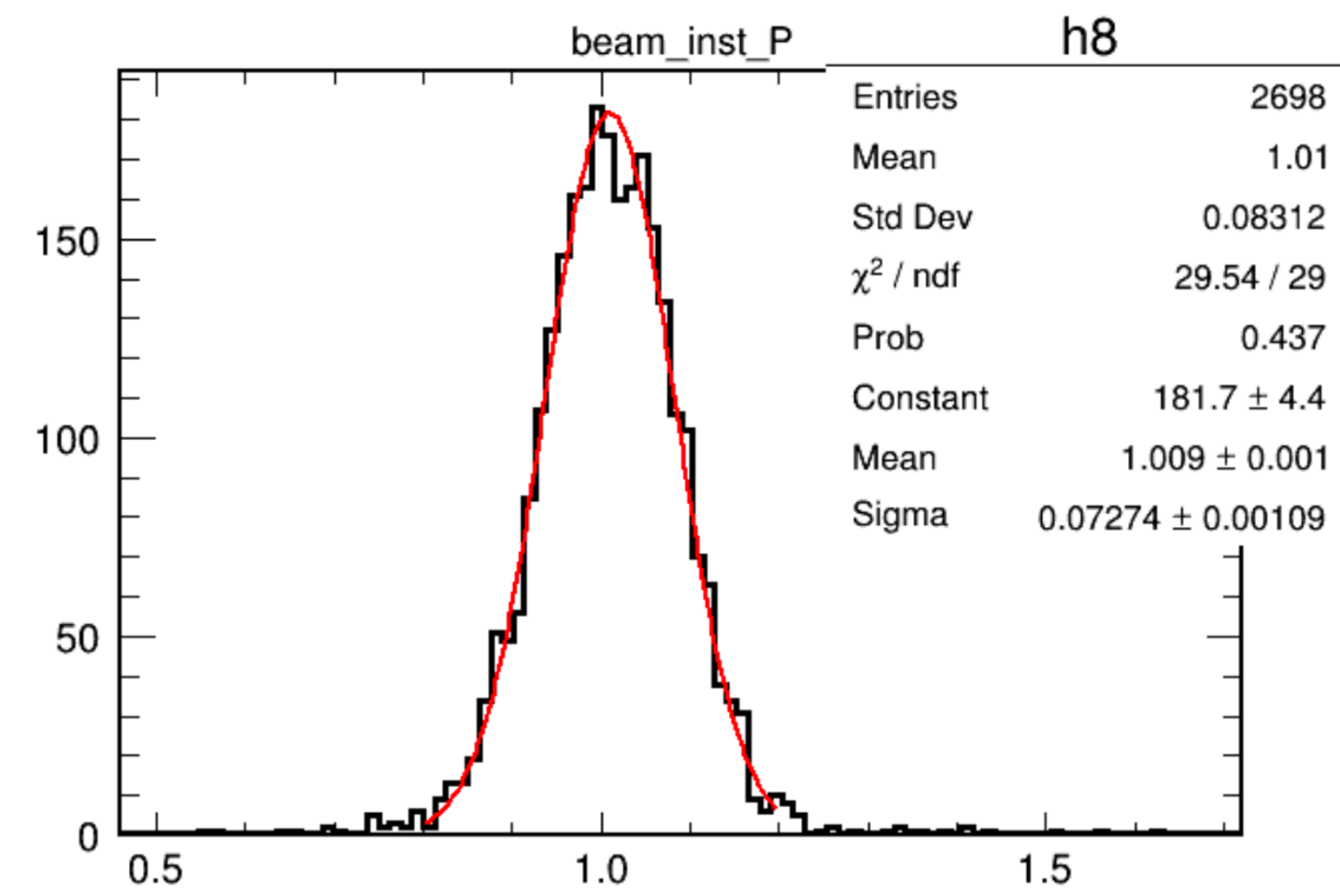
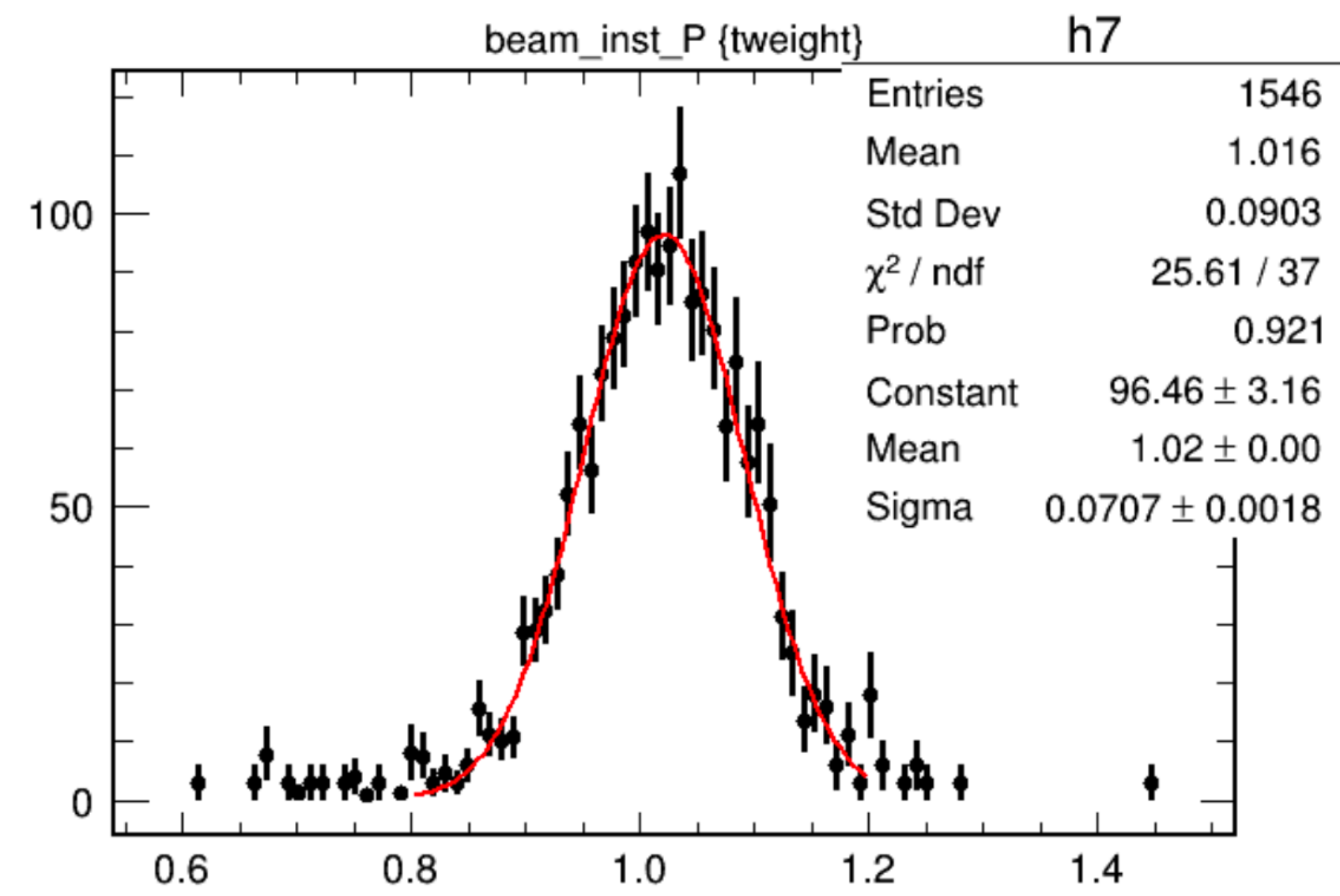
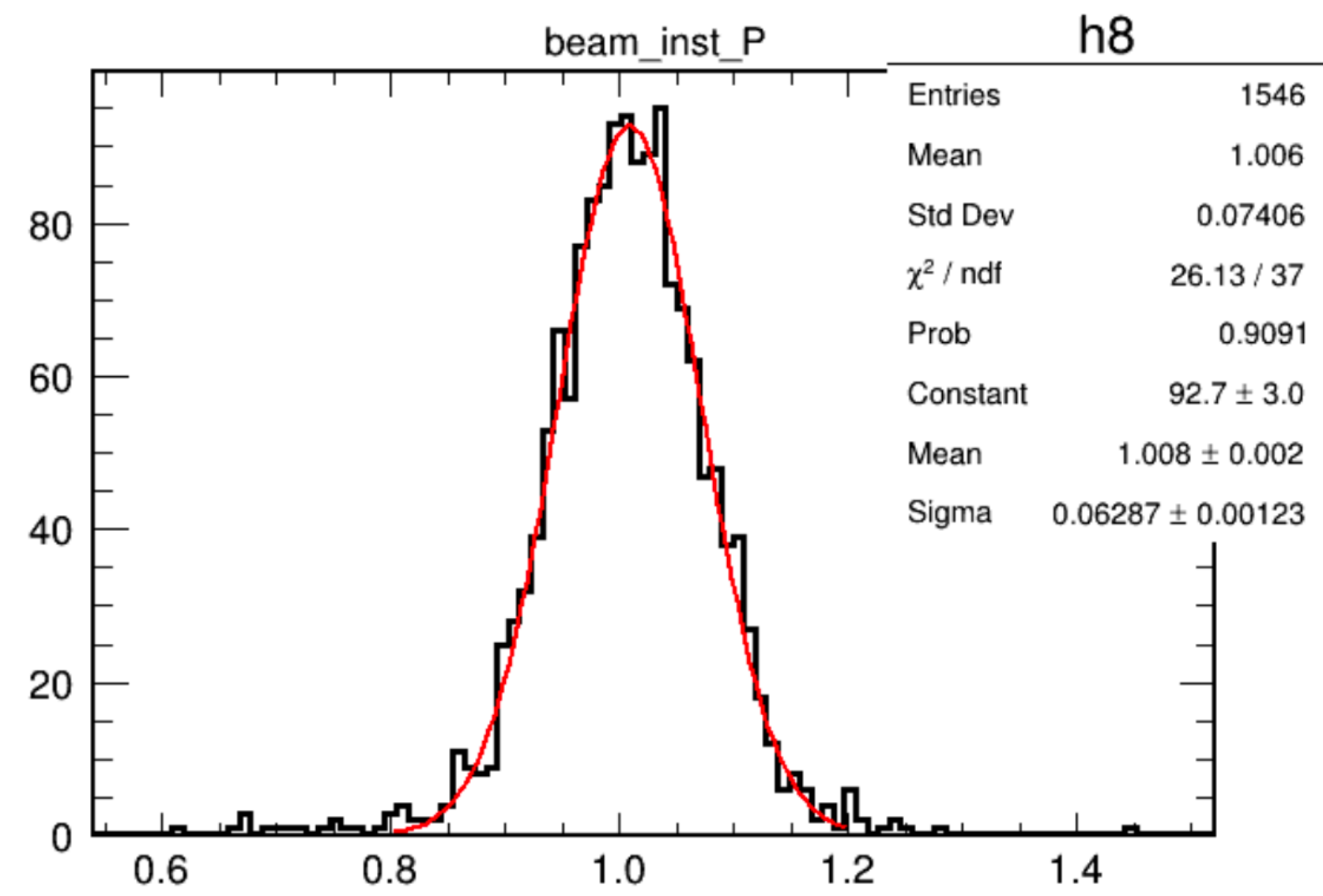
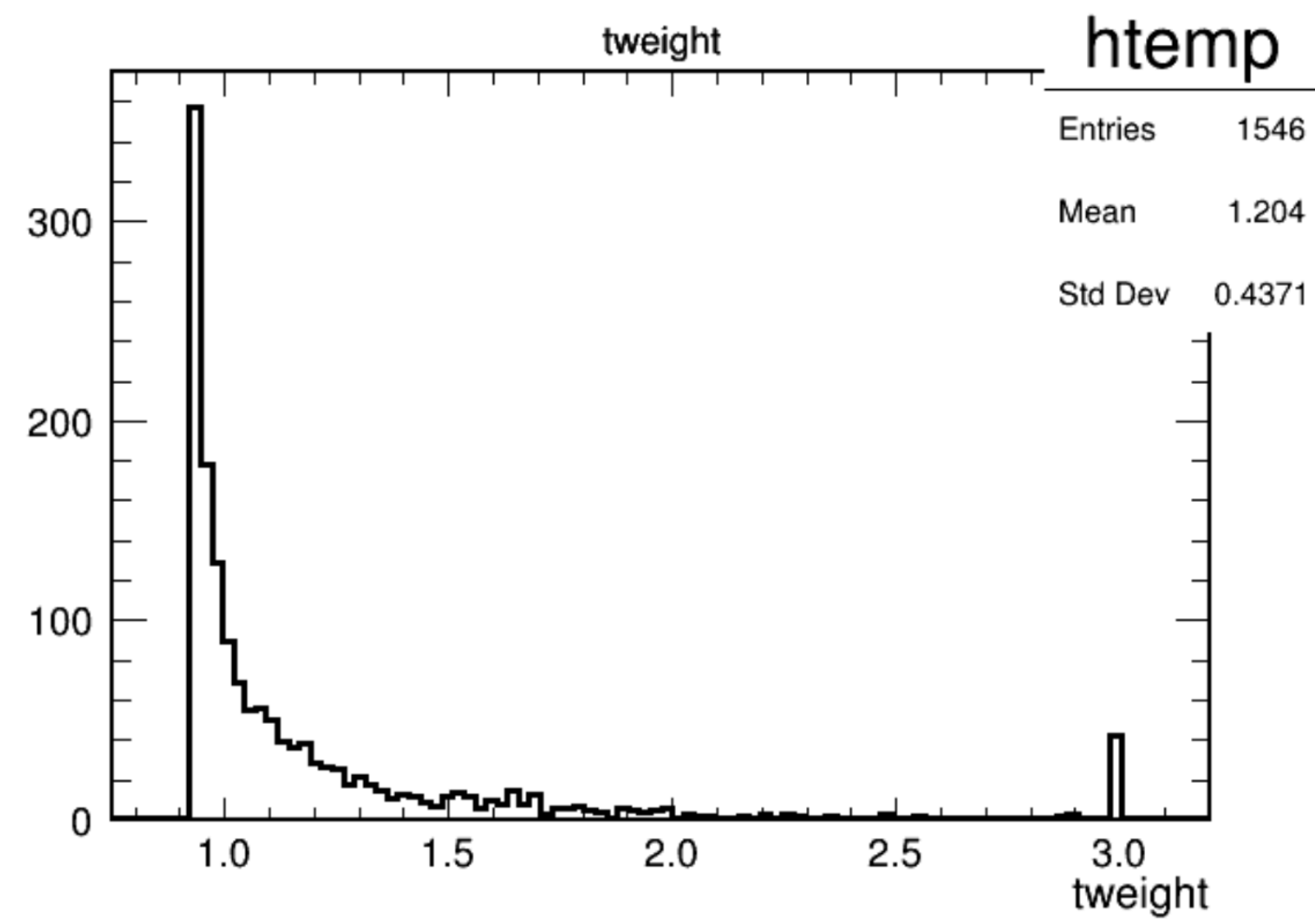


Before muon cuts



After muon cuts



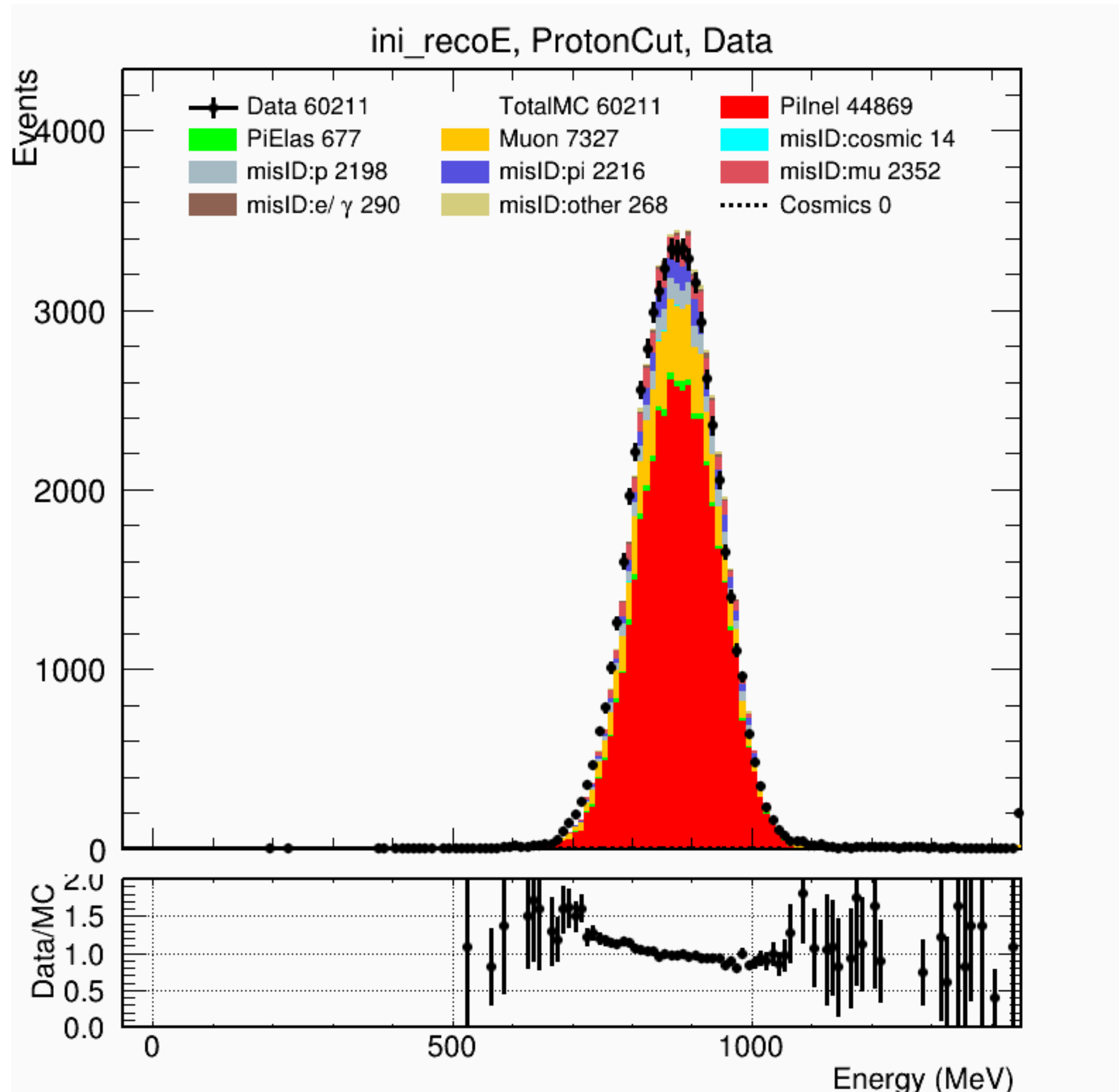


An extra smearing

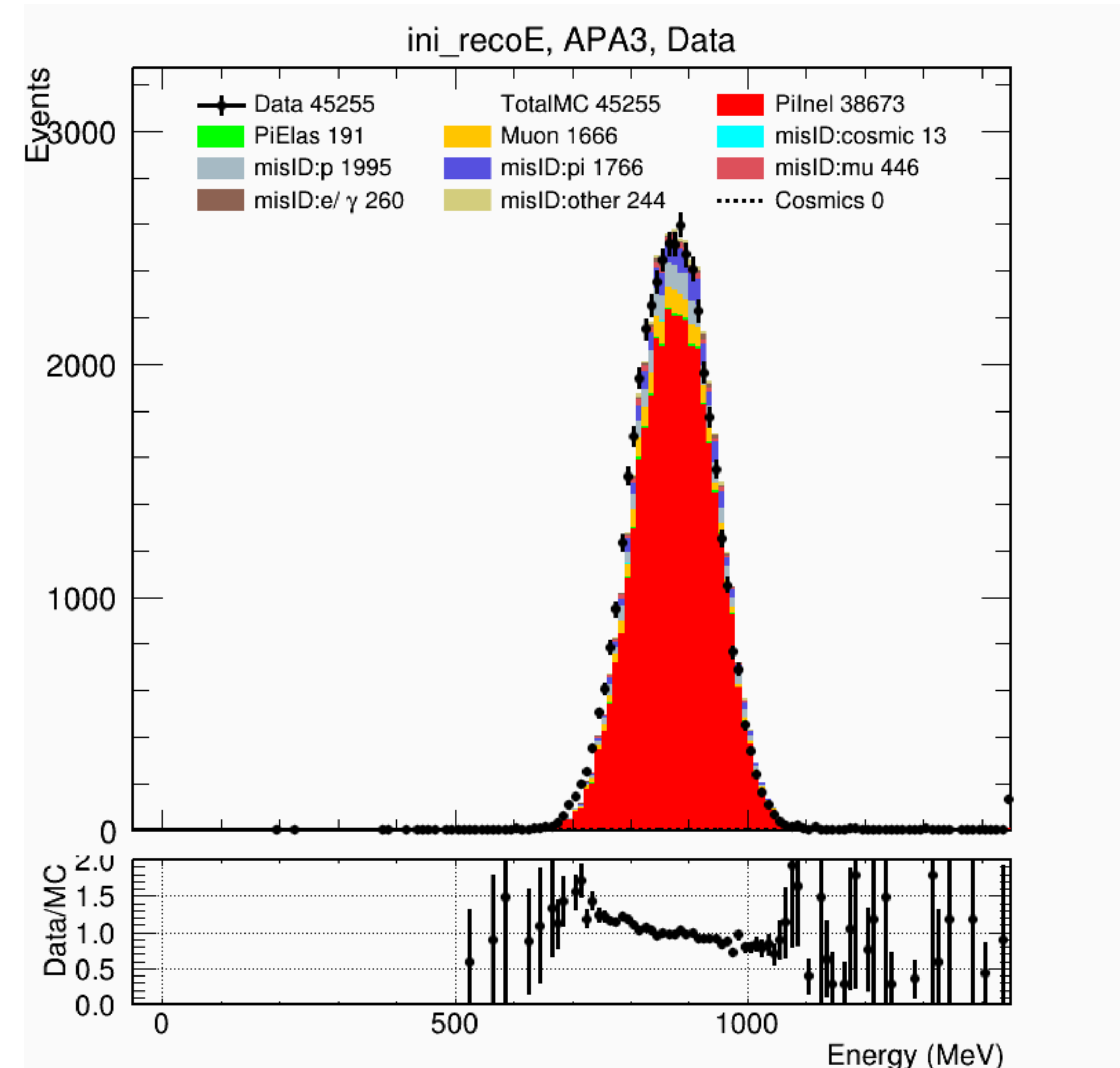
- The remaining difference in beam instrumented momentum σ could be due to data/MC difference in resolution.
- Still using the stopping muon sample
 - Fit **data instrumented** beam momentum with a Gaus(μ_1, σ_1)
 - Fit **MC instrumented** beam momentum with a Gaus(μ_2, σ_2)
 - Convolute an extra smearing $\sigma = \sqrt{\sigma_1^2 - \sigma_2^2}$ in MC. (Add a random Gaus(0, σ) to **MC instrumented** beam momentum). Now we should have the same KEff.
- The difference between μ_1 and μ_2 could be due to difference in upstream E loss, but it's not needed since we've aligned the front-face KE.

Results

weight=Gaus(1018.18, 71.92)/Gaus(1003.3, 60.9), and an extra smearing Gaus(0,17.8) in MC beam_inst_P



Before muon cuts

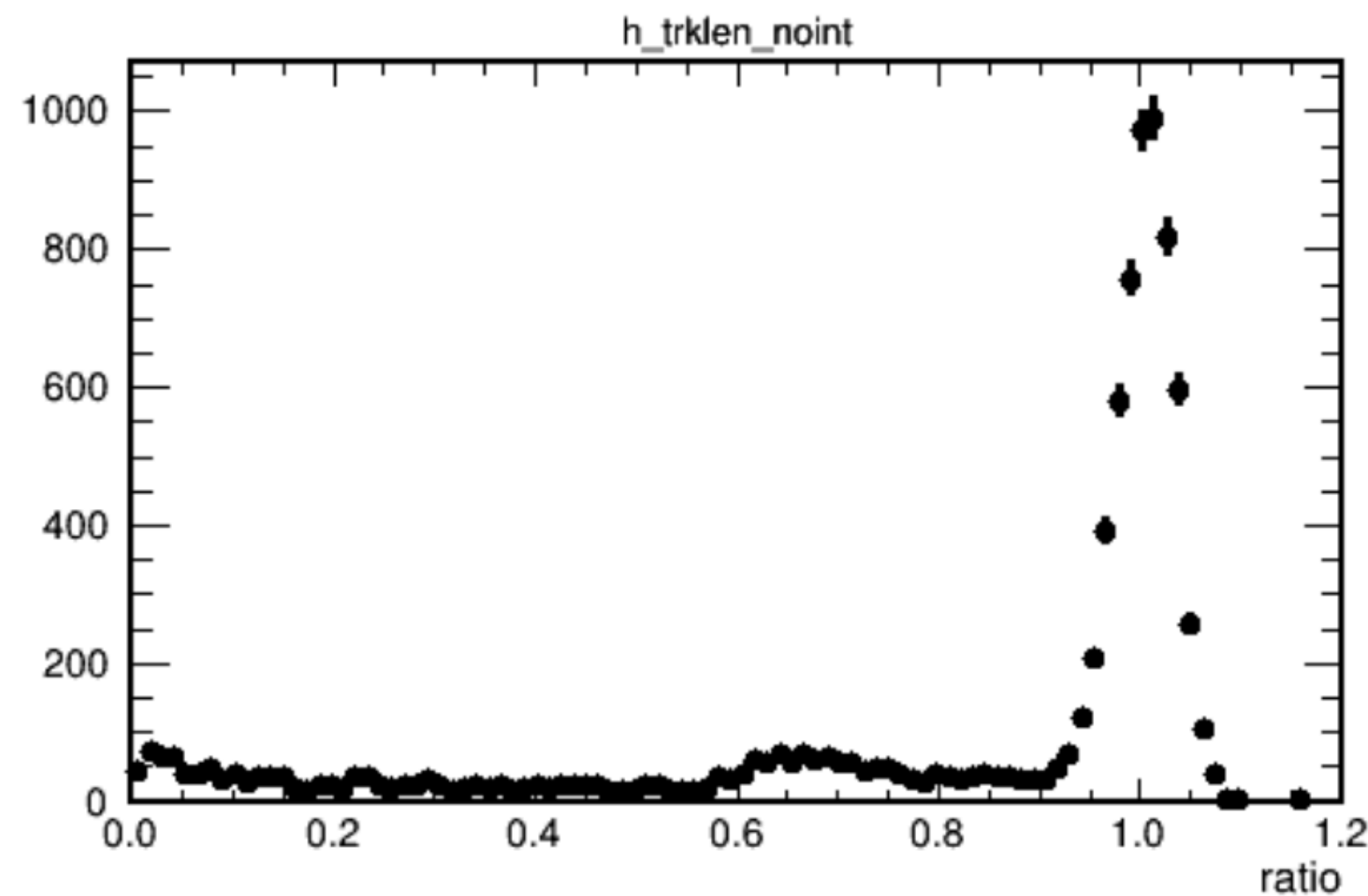


After muon cuts

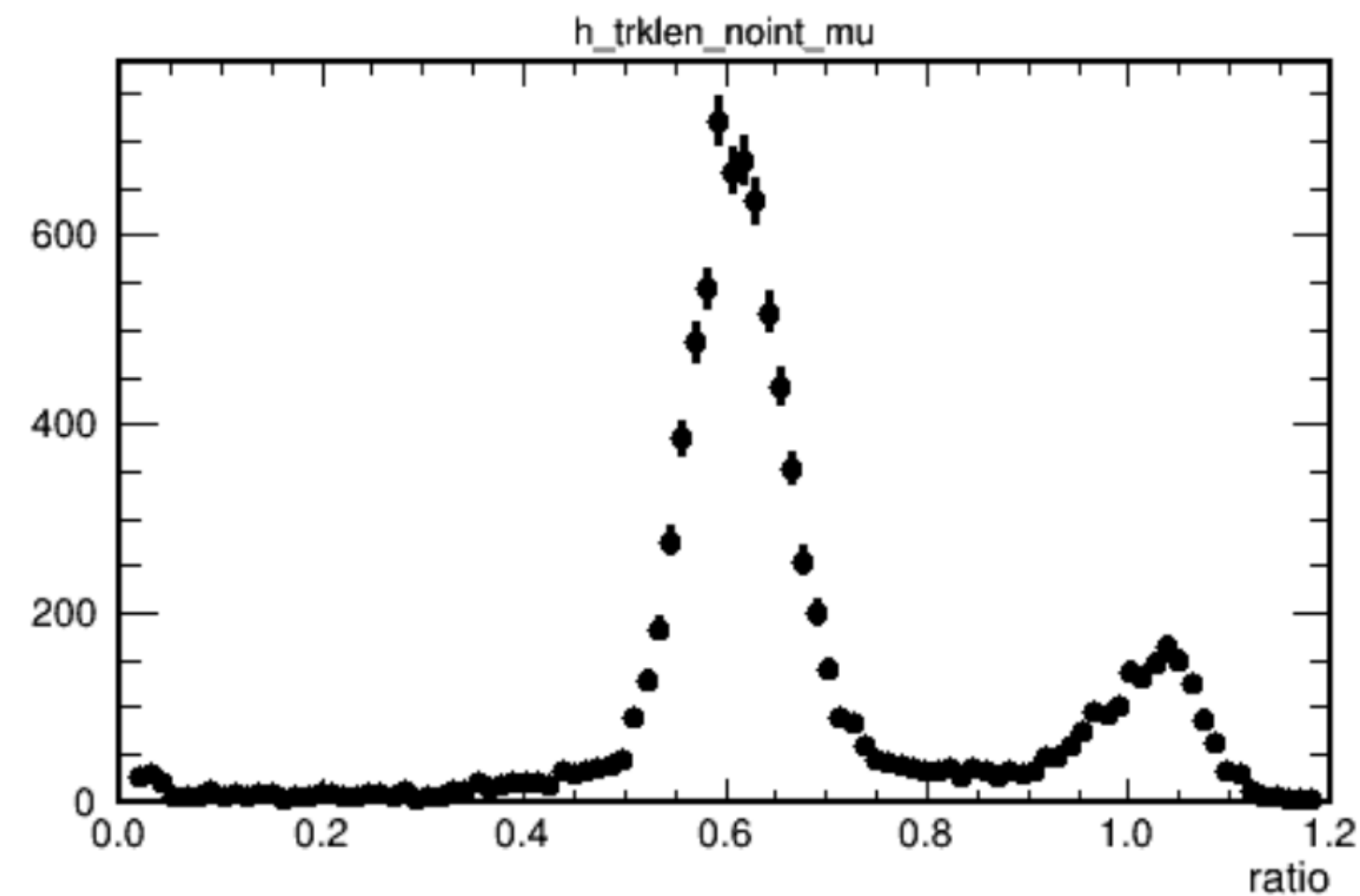
Back-ups

Stopping beam muon sample

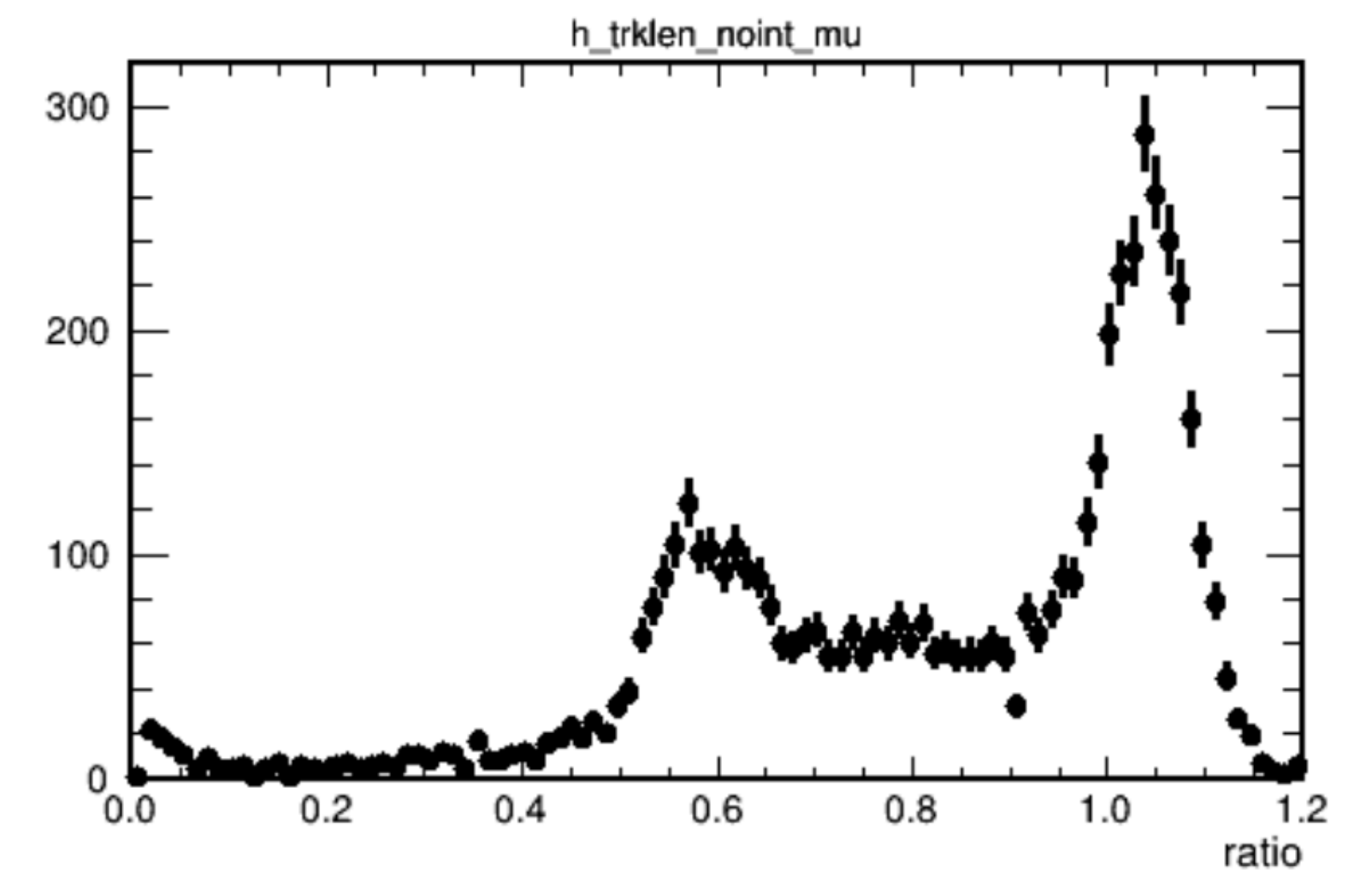
- BeamQualityCut && Michel_score > 0.6
- Ratio = $\text{trklen} / \text{RangeFromKE}(\text{Eff})$



MC true



MC reco



Data reco

Select Ratio > 0.9 as stopping muon sample

